Toohong

Triacs sensitive gate

BT139 series E

GENERAL DESCRIPTION

Glass passivated, sensitive gate triacs in a plastic envelope, intended for use in general purpose bidirectional switching and phase control applications, where high sensitivity is required in all four quadrants.

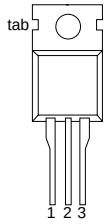
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	MAX.	UNIT
	BT139-	**500E**	**600E**	**800E**	
V_{DRM}	Repetitive peak off-state voltages	500	600	800	V
$I_{T(RMS)}$	RMS on-state current	16	16	16	A
I_{TSM}	Non-repetitive peak on-state current	140	140	140	A

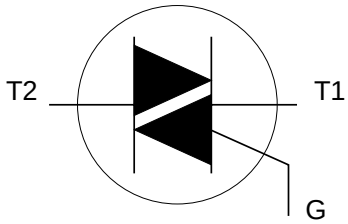
PINNING - TO220AB

PIN	DESCRIPTION
1	main terminal 1
2	main terminal 2
3	gate
tab	main terminal 2

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS		MIN.	MAX.			UNIT
					-500	**-600**	**-800**	
V_{DRM}	Repetitive peak off-state voltages			-	500[1]	600[1]	800	V
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_{mb} \leq 99$ ˚C		-		16		A
I_{TSM}	Non-repetitive peak on-state current	full sine wave; $T_j = 25$ ˚C prior to surge						
		t = 20 ms		-		140		A
		t = 16.7 ms		-		150		A
I^2t	I^2t for fusing	t = 10 ms		-		98		A^2s
dI_T/dt	Repetitive rate of rise of on-state current after triggering	I_{TM} = 20 A; I_G = 0.2 A; dI_G/dt = 0.2 A/µs						
			T2+ G+	-		50		A/µs
			T2+ G-	-		50		A/µs
			T2- G-	-		50		A/µs
			T2- G+	-		10		A/µs
I_{GM}	Peak gate current			-		2		A
V_{GM}	Peak gate voltage			-		5		V
P_{GM}	Peak gate power			-		5		W
$P_{G(AV)}$	Average gate power	over any 20 ms period		-		0.5		W
T_{stg}	Storage temperature			-40		150		˚C
T_j	Operating junction temperature			-		125		˚C

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th\ j\text{-}mb}$	Thermal resistance junction to mounting base	full cycle	-	-	1.2	K/W
		half cycle	-	-	1.7	K/W
$R_{th\ j\text{-}a}$	Thermal resistance junction to ambient	in free air	-	60	-	K/W

STATIC CHARACTERISTICS

T_j = 25 ˚C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	MAX.	UNIT
I_{GT}	Gate trigger current	V_D = 12 V; I_T = 0.1 A					
			T2+ G+	-	2.5	10	mA
			T2+ G-	-	4.0	10	mA
			T2- G-	-	5.0	10	mA
			T2- G+	-	11	25	mA
I_L	Latching current	V_D = 12 V; I_{GT} = 0.1 A					
			T2+ G+	-	3.2	30	mA
			T2+ G-	-	16	40	mA
			T2- G-	-	4.0	30	mA
			T2- G+	-	5.5	40	mA
I_H	Holding current	V_D = 12 V; I_{GT} = 0.1 A		-	4.0	30	mA
V_T	On-state voltage	I_T = 20 A		-	1.2	1.6	V
V_{GT}	Gate trigger voltage	V_D = 12 V; I_T = 0.1 A		-	0.7	1.5	V
		V_D = 400 V; I_T = 0.1 A; T_j = 125 ˚C		0.25	0.4	-	V
I_D	Off-state leakage current	V_D = $V_{DRM(max)}$; T_j = 125 ˚C		-	0.1	0.5	mA

DYNAMIC CHARACTERISTICS

T_j = 25 ˚C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
dV_D/dt	Critical rate of rise of off-state voltage	V_{DM} = 67% $V_{DRM(max)}$; T_j = 125 ˚C; exponential waveform; gate open circuit	-	50	-	V/µs
t_{gt}	Gate controlled turn-on time	I_{TM} = 20 A; V_D = $V_{DRM(max)}$; I_G = 0.1 A; dI_G/dt = 5 A/µs	-	2	-	µs

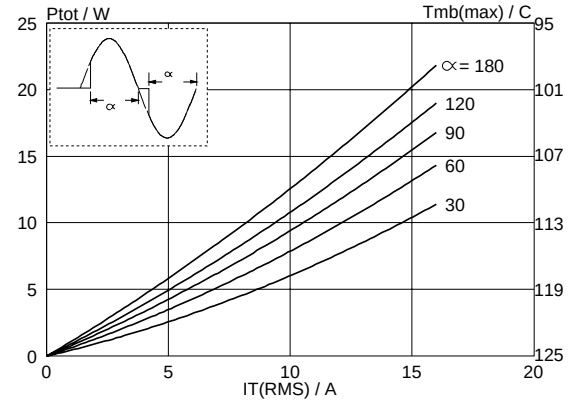


Fig.1. Maximum on-state dissipation, P_{tot}, versus rms on-state current, $I_{T(RMS)}$, where α = conduction angle.

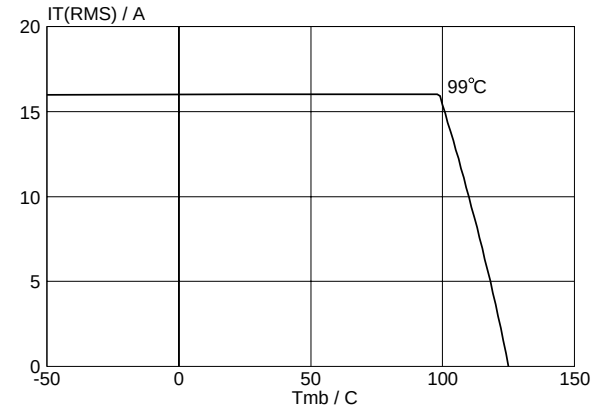


Fig.4. Maximum permissible rms current $I_{T(RMS)}$, versus mounting base temperature T_{mb}.

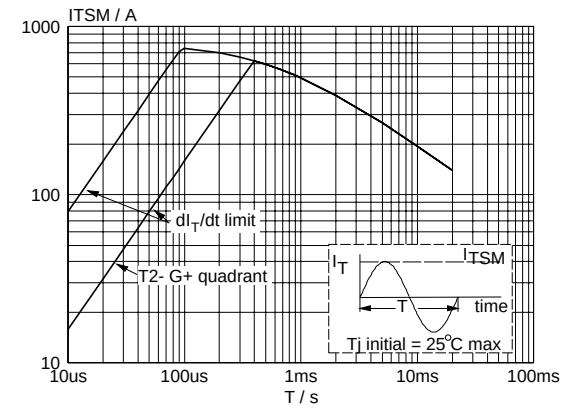


Fig.2. Maximum permissible non-repetitive peak on-state current I_{TSM}, versus pulse width t_p, for sinusoidal currents, $t_p \leq 20ms$.

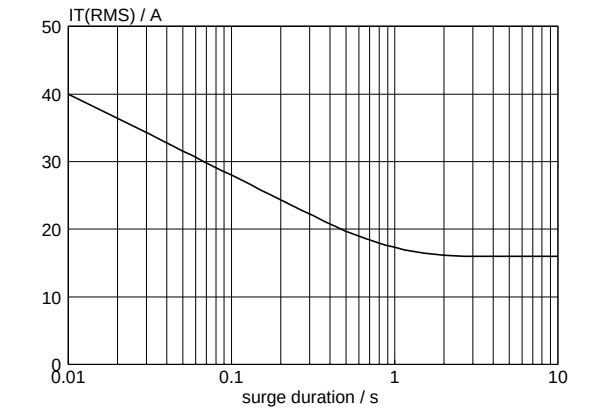


Fig.5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, f = 50 Hz; $T_{mb} \leq 99˚C$.

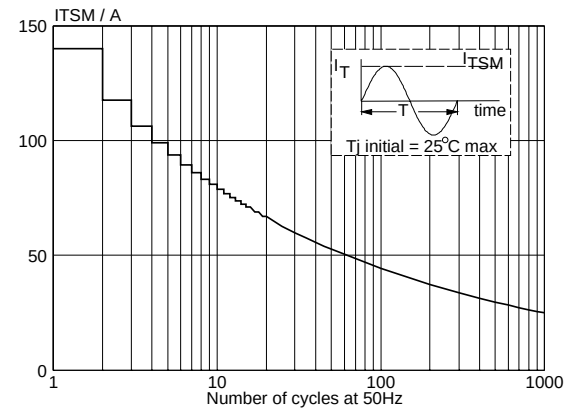


Fig.3. Maximum permissible non-repetitive peak on-state current I_{TSM}, versus number of cycles, for sinusoidal currents, f = 50 Hz.

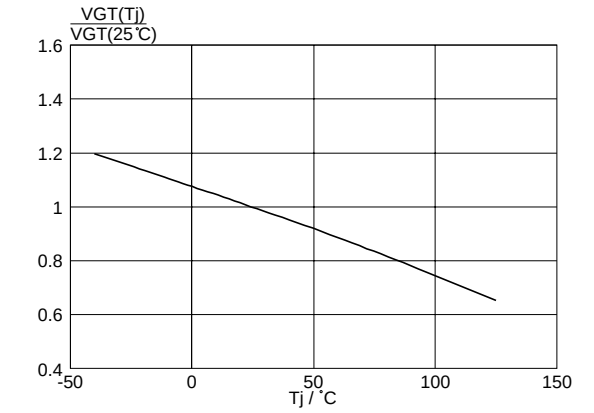


Fig.6. Normalised gate trigger voltage $V_{GT}(T_j)/ V_{GT}(25˚C)$, versus junction temperature T_j.

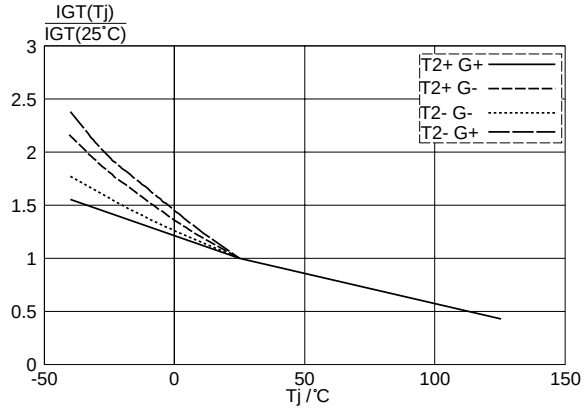


Fig.7. Normalised gate trigger current $I_{GT}(T_j)/ I_{GT}(25^{\circ}C)$, versus junction temperature T_j.

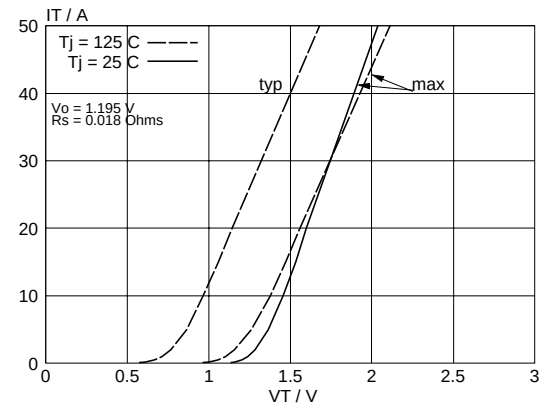


Fig.10. Typical and maximum on-state characteristic.

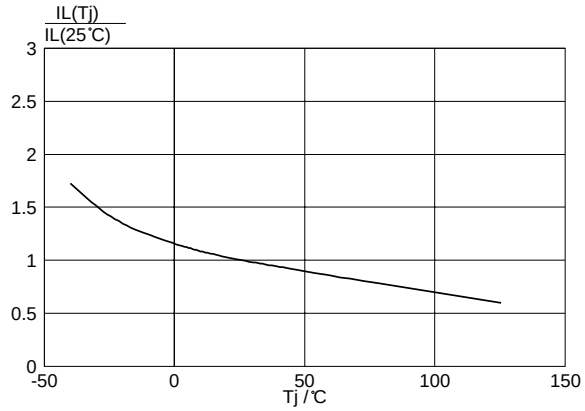


Fig.8. Normalised latching current $I_L(T_j)/ I_L(25^{\circ}C)$, versus junction temperature T_j.

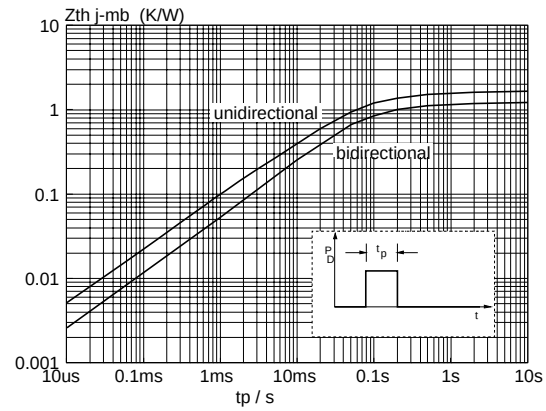


Fig.11. Transient thermal impedance $Z_{th\ j\text{-}mb}$, versus pulse width t_p.

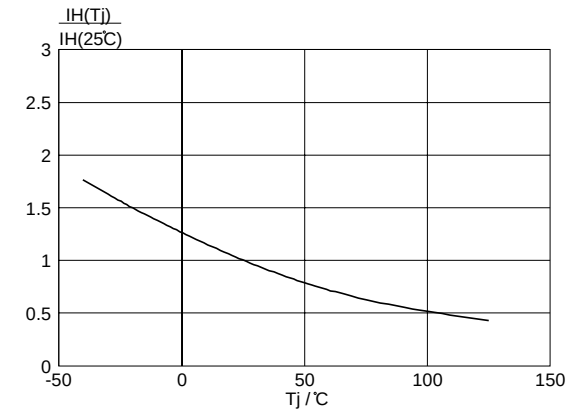


Fig.9. Normalised holding current $I_H(T_j)/ I_H(25^{\circ}C)$, versus junction temperature T_j.

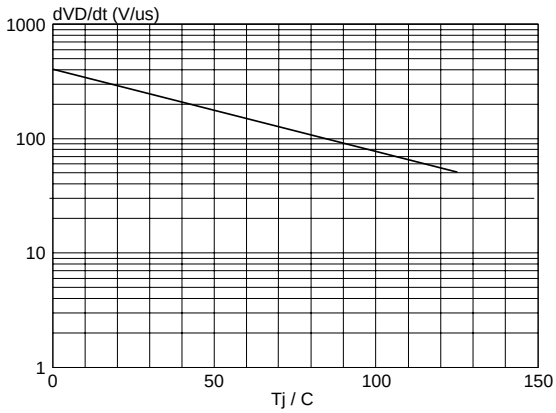


Fig.12. Typical, critical rate of rise of off-state voltage, dV_D/dt versus junction temperature T_j.